

ESD TEST REPORT

Field-Induced Charged-Device Model

JS-002-2018

ANSI/ESDA/JEDEC Standard, Method JS-002-2018 is an ESD test using Field-Induced Charged-Device Model, three positive and three negative pulses applied to the devices per customer's specification with 0.5 second cool down between pulses.

Customer : **Alpha & Omega Semiconductor (Shanghai), Ltd.**

Address: Building 8 & 9, No. 91, Lane 109, Rong Kang Road,
Songjiang Export Processing Zone, Zone B, # 888 Song Zheng Highroad, Shanghai

Device Information

Part No. :	AOCA33102E	Sample Size :	3pcs
Package Type :	AlphaDFN3X2.74-14L	Pin Count :	14
Lot No. :	0B06	Date Code :	-
VDD Domains :	S2 S1	VSS Domains :	S1 S2

Test Equipment

Tester1 :	ZAPMASTER MK.2 SE	Serial No. :	0508317
Calibration Date :	Jan 15 th 2020	Expiration Date :	Jan 14 th 2021
Tester2 :	Orion Robotic CDM Test System	Serial No. :	0806294
Calibration Date :	Jan 16 th 2020	Expiration Date :	Jan 15 th 2021

Environmental Condition

Temperature :	23°C	Humidity :	30% RH
Submit date :	Nov 23 rd 2020	Complete date :	Nov 24 th 2020


Stress Summary

CDM			
Sample No.	Voltage Level	Process	Spot Test Results* (Within 10μA @ 8V between G and S2/S1)
9#	±2kV	All Pins Done	PASS
10#		All Pins Done	PASS
11#		All Pins Done	PASS

Test Result*

Model	Pin Combinations	ESD Sensitivity Pass*: 2kV	V Class: C3
CDM	ALL PINS DONE	±2kV	JS-002-2018 Class C0a: <125V Class C0b: 125V to <250V Class C1: 250 to <500 V Class C2a: 500 to <750 V Class C2b: 750 to <1000 V Class C3: ≥1000V

*Note: Results will be updated based on customer final electrical test results.

Test Engineer: Fei Teng	Date: Nov 24 th 2020
Approved by FA Manager: 	Date: Nov 24 th 2020



Recommendations

EAG Shanghai certifies that above tests have been performed in accordance to the requirements stated above and per the customer purchase order and applicable documents.

EAG Shanghai recommends electrical testing as a validation of reported results. Curve Trace criteria was utilized to specify a pass or fail. Industry standards require the device to be tested functionally at post stress and should continue to meet all electrical parameters as per the data sheet.

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